

PSG INSTITUTE OF ADVANCED STUDIES

Nanotech Research, Innovation and Incubation centre

Rules and Charges of SPM Facility Usage

1. Multimode Scanning Probe Microscope, AFM/STM (NT-MDT)

AFM Imaging: Contact / Semi-contact mode

Special Techniques available:

In Air and Vacuum: Scanning Tunneling Microscopy (STM), Lateral Force Microscopy (LFM), Phase Imaging, Force Modulation, Magnetic Force Microscopy (MFM), Adhesion force imaging, AFM Lithography, Spreading Resistance Imaging (SRI), Scanning Kelvin Probe Microscopy (SKM), Heating Stage Operations, Nanosclerometry with AFM-Nanoindentation.

In Liquid: Contact AFM/LFM/Adhesion Force Imaging/Force Modulation, Resonant Mode, Phase Imaging, AFM Lithography, Electrochemical AFM/STM Imaging

Faculty in charge: Dr. P.Biji, Assistant Professor in Nanotechnology, PSGIAS

Email: pbm@psgias.ac.in

2. Bench-top Scanning Probe Microscope, AFM/STM (Nanosurf)

AFM Imaging: Contact Mode, STM: imaging in air

Faculty in charge: Dr. R.Selvakumar, Assistant Professor in Nanobiotechnology, PSGIAS

Email: rsk@psgias.ac.in

Researchers from various institutions are welcome to use these facilities. Those who want to avail these facilities are requested to send the filled job requisition form (Downloadable from PSGIAS website) and advance DD/Cheque (if applicable) in favour of “**PSG Centre for Sponsored Research & Consultancy**” payable at Coimbatore to:

Mrs. Uma Maheswari

PSG Institute of Advanced Studies

PB No: 1609, Peelamedu

Coimbatore-641 004

E-mail: uma@psgias.ac.in, Phone: 0422-4344000 (Extn: 4541)

Rules and Charges for using the facility

1. To avail any facility prior registration is a must.
2. Analysis will be done on charge basis.
3. Appointment will be given as per queue and the allotted time for the slot will be informed through E-mail.

4. For a better analysis, basic details about the sample should be given.
5. Refunds will not be made in any case.
6. Sample preparation should be done by the user.
7. External colleges & Universities and industry users should pay the charges in advance along with the samples for characterization

8. Analysis Charges:

Multimode SPM (NTMDT)-Imaging and Special techniques-analysis charges

Modes	Internal (PSG Institutions (INR) +18% GST	External Colleges & Universities (INR) +18% GST	Industry (INR) +18% GST
Atomic Force Microscopy (AFM)	1000	3000	6000
Lateral Force Microscopy (LFM)	1000	3000	6000
Spreading Resistance Imaging (SRI)	1500	3500	7000
Force Modulation mode	1000	3000	6000
Phase imaging	1000	3000	6000
Adhesion Force Imaging	1250	3250	6500
Magnetic Force Microscopy (MFM)	2000	4000	8000
Electric Force Microscopy (EFM)	1500	3500	7000
Kelvin Probe Microscopy	1500	3500	7000
Scanning Capacitance Imaging (SCI)	1500	3500	7000
Heating Stage operations	2000	4000	8000
Nanoindentation	2000	4000	8000
Liquid stage Operations	1500	3500	7000
In Vacuum condition	2000	4000	8000
Scanning Tunneling Microscopy	1500	3500	7000
Electrochemical STM	2000	4000	8000
Lithography	2000	4000	8000
AFM/ STM (Nanosurf)	625	1250	2500